

**Search Notes**

Application/Control No.

10/749,448

Examiner

Hai L. Nguyen

Applicant(s)/Patent under  
Reexamination

KIM ET AL.

Art Unit

2816

**SEARCHED**

Class	Subclass	Date	Examiner
327	153-155, 158,159, 161-163, 165	2/17/2005	HLN
	141,144		
	149,152		
	261,269		
	270,271		
	276-278		
	284,291		
331	1A,12,25	2/19/2005	
✓	1R	—	
375	373-376	✓	

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Shepardize Search	2/21/2005	HLN
EAST Text Search	—	—